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|-------------------------------------|--|-------------------------|---|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/708,879 | WEI ET AL. | |
| Examiner /Robert James Popovics/ | | Art Unit 1797 | Page 1 of 3 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------------|----------------|
| * | A | US-3,058,895 A | 10-1962 | WILLIAMS LYNN A | 205/653 |
| * | B | US-5,045,161 A | 09-1991 | McGregor, Gavin | 205/663 |
| * | C | US-5,177,335 A | 01-1993 | Hartwig et al. | 219/69.14 |
| * | D | US-5,281,788 A | 01-1994 | Abiko et al. | 219/69.14 |
| * | E | US-5,298,161 A | 03-1994 | Sieg, Arno | 210/321.78 |
| * | F | US-5,434,381 A | 07-1995 | Mitcheson, George R. | 219/69.14 |
| * | G | US-5,685,971 A | 11-1997 | Schroder et al. | 205/642 |
| * | H | US-5,739,497 A | 04-1998 | Tanaka, Dwight | 219/69.14 |
| * | I | US-5,798,492 A | 08-1998 | Enya et al. | 219/69.14 |
| * | J | US-5,935,457 A | 08-1999 | Kita et al. | 219/69.14 |
| * | K | US-5,993,663 A | 11-1999 | Maidagan Larrumbide, Javier | 210/666 |
| * | L | US-2002/0079213 A1 | 06-2002 | Demellayer, Rene | 204/238 |
| * | M | US-6,427,848 B1 | 08-2002 | Shih, Chiao-Chin | 210/533 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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NON-PATENT DOCUMENTS

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|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

| | | | | |
|-----------------------------------|--|---------------------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. 10/708,879 | Applicant(s)/Patent Under Reexamination WEI ET AL. | |
| | | Examiner /Robert James Popovics/ | Art Unit 1797 | Page 2 of 3 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-2002/0148814 A1 | 10-2002 | Ishiwata et al. | 219/69.2 |
| * | B | US-6,533,927 B1 | 03-2003 | Hosaka, Akio | 210/97 |
| * | C | US-6,806,435 B2 | 10-2004 | Ishiwata et al. | 219/69.2 |
| * | D | US-2004/0238417 A1 | 12-2004 | Arakawa et al. | 210/085 |
| * | E | US-2004/0262266 A1 | 12-2004 | Ishiwata et al. | 219/069.2 |
| * | F | US-2005/0023195 A1 | 02-2005 | Kita et al. | 210/086 |
| * | G | US-2005/0077269 A1 | 04-2005 | Yokomichi, Shigeharu | 219/069.2 |
| * | H | US-6,897,400 B1 | 05-2005 | Yuan et al. | 219/69.15 |
| * | I | US-6,933,456 B2 | 08-2005 | Yokomichi, Shigeharu | 219/69.17 |
| * | J | US-2005/0218089 A1 | 10-2005 | Wei et al. | 210/805 |
| * | K | US-2005/0247569 A1 | 11-2005 | Lamphere et al. | 205/663 |
| * | L | US-7,175,756 B2 | 02-2007 | Kita et al. | 210/86 |
| * | M | US-7,202,439 B2 | 04-2007 | Ishiwata et al. | 219/69.14 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
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| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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|-----------------------------------|--|---------------------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. 10/708,879 | Applicant(s)/Patent Under Reexamination WEI ET AL. | |
| | | Examiner /Robert James Popovics/ | Art Unit 1797 | Page 3 of 3 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-7,214,901 B1 | 05-2007 | Ball et al. | 219/69.17 |
| * | B | US-2007/0175814 A1 | 08-2007 | Kita et al. | 210/421 |
| * | C | US-2007/0256939 A1 | 11-2007 | Wei et al. | 205/674 |
| * | D | US-7,329,825 B2 | 02-2008 | Awakura, Yuichi | 219/69.15 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
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FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.